

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		09/929,995	TERNULLO ET AL.	
Examiner		Art Unit	Page 1 of 1	
Sargon N. Nano		2157		

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,647,269	11-2003	Hendrey et al.	455/456.3
	B	US-6,738,951	05-2004	Weiss et al.	715/523
	C	US-6,857,013	02-2005	Ramberg et al.	709/223
	D	US-6,505,046	01-2003	Baker, Steven F.	455/456.3
	E	US-6,397,057	05-2002	Malackowski et al.	455/414.1
	F	US-6,381,465	04-2002	Chern et al.	455/466
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.